Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/622,116	MEIER ET AL.	
Examiner	Art Unit	
Thomas D. Lee	2625	

Thomas D. Lee

SEARCHED						
SEARCHED						
Class	Subclass	Date	Examiner			
382	162, 176	4/26/2007	TDL			
358	504, 518	4/26/2007	TDL			
358	520	4/26/2007	TDL			
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INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
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	Subclass	Subclass Date			

SEARCH N (INCLUDING SEARC)
	DATE	EXMR
EAST Search History Printout	4/26/2007	TDL
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